

09/708490  
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Class	Subclass
ISSUE CLASSIFICATION	

# U.S. UTILITY Patent Application

QI/PE	PATENT DATE
AK SCANNED	Q.A. BW

APPLICATION NO. 09/708490	CONT/PRIORS F	CLASS 498 702	SUBCLASS UNIT 825	ART UNIT 2803	EXAMINER LAW
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APPLICANTS  
TITLE: Chie Iwasa

TITLE: Semiconductor testing method and semiconductor testing apparatus for semiconductor devices, and program for executing semiconductor testing method

PTO-2040  
12/99

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ISSUING CLASSIFICATION							
ORIGINAL		CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
INTERNATIONAL CLASSIFICATION							

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	_____ (Assistant Examiner)    _____ (Date)			<b>NOTICE OF ALLOWANCE MAILED</b>	
	_____ (Primary Examiner)    _____ (Date)			<b>ISSUE FEE</b> Amount Due    Date Paid	
	_____ (Legal Instruments Examiner)    _____ (Date)			<b>ISSUE BATCH NUMBER</b>	

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